Compliant with IEC 62474/ D9.00

Semiconductor Device Type:	003 TO-263 MatteTin	Termination Base Alloy: Copper Alloy (Cu)			Package Homogeneous Materials				J-STD-609A Product Marking and/or Pkg. Labeling e3	
''		"Contained In"	% Total			1205.02	(mg) Total	Mold Compound	% ot Total Weight	t 79.75
Basic Substance	CAS Number	Sub-Component	Weight	mg/part	ppm	1205.02	(ilig) rotal	word Compound	% of Total Weight	1 79.75
Silica, vitreous	60676-86-0	Mold Compound	67.788	1024.269	677,875		Silica, vitreous	60676-86-0	85.00	
Epoxy Resin	Trade Secret	Mold Compound	4.885	73.808	48,847		Epoxy Resin	Trade Secret	6.13	
Phenolic Resin	Trade Secret	Mold Compound	4.885	73.808	48,847		Phenolic Resin	Trade Secret	6.13	
Epoxy, Cresol Novolac	29690-82-2	Mold Compound	1.954	29.523	19,539		Epoxy, Cresol Novolac	29690-82-2	2.45	
Carbon Black	1333-86-4	Mold Compound	0.239	3.615	2,393		Carbon Black	1333-86-4	0.30	
Copper	7440-50-8	Lead Frame	9.984	150.853	99,837			Total	100.00	
Iron	7439-89-6	Lead Frame	0.246	3.711	2,456	157.90	(mg) Total	Lead Frame	% of Total Weight	t 10.45
Silver	7440-22-4	Lead Frame	0.199	3.008	1,991		Copper	7440-50-8	95.54	1
Zinc	7440-66-6	Lead Frame	0.013	0.197	131		Iron	7439-89-6	2.35	
Phosphorous	7723-14-0	Lead Frame	0.009	0.130	86	1	Silver	7440-22-4	1.91	1
Lead	7439-92-1	Die Attach	0.716	10.823	7.163		Zinc	7440-66-6	0.13	1
Silver	7440-22-4	Die Attach	0.019	0.283	188		Phosphorous	7723-14-0	0.08	
Tin	7440-31-5	Die Attach	0.015	0.227	150	•		Total	100.00	의)
Silicon	7440-21-3	Chip (Die)	7.500	113.325	75,000	11.33	(mg) Total	Die Attach	% of Total Weight	
						High Temp solder	Lead	7439-92-1	95.50	1
Gold	7440-57-5	Wire Bond	0.300	4.533	3,000					1
Tin	7440-31-5	Plating on external leads (pins) - Matte Tin / annealed at 150°C for 1 hour	1.250	18.888	12,500	Excemption 7a	Silver	7440-22-4	2.50	
		TOTALS:	100.000	1,511.000	1,000,000		Tin	7440-31-5	2.00	
	h EU Directives: 20					442.22		Total	100.00	
5)) and 2002/53/EC (End-of-Life Vehicles (ELV) using EU-RoHS ap ght or more lead. npliance with the above EU Directives has been verified via interna	h EU Directives: 20 plication exemptio al design controls,	002/95/EC (27 January 2003) & Directive 2011/65/EU (08 Jun n 7(a): Lead in high melting temperature type solders (i.e. le supplier declarations, and /or analytical test data.	ead-based alloy	ys containing	85% by	113.33	Total (mg) Doped Silicon		100.00 % of Total Weight 100.00	t 7.5
(i)) and 2002/53/EC (End-of-Life Vehicles (ELV) using EU-RoHS applit or more lead. Interpolation with the above EU Directives has been verified via internate themical substance is absent from the list above, the chemical surporated's knowledge and belief as of the date of this document, below the threshold of regulatory concern for any regulatory scheing compounds used by Microchip meet the UL94 V0 flammabilits/l/ul.com/global/eng/pages/offerings/industries/chemicals/plastics	th EU Directives: 20 plication exemption al design controls, bstance is NOT and there is no credible time world-wide. y standard for plass of	002/95/EC (27 January 2003) & Directive 2011/65/EU (08 Jun n 7(a): Lead in high melting temperature type solders (i.e. le supplier declarations, and /or analytical test data. intentional ingredient in the semiconductor device and, to te reason to believe that the unavoidable impurity concentrations. You can access the UL iQTM family of databases to ob-	the best of Mic tion of the che otain a test rep	crochip Technomical substan	85% by ology ice, if any, is	113.33	Total (mg) Doped Silicon (mg) Total	Total Chip (Die) 7440-21-3 Total Wire Bond	% of Total Weight 100.00 100.00 % of Total Weight	t 7.5
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